NO 3, Pau-Tou-Tsuo Valley, Chia-Pau Tsuen, Lin Kou Hsiang, Taipei County, Taiwan, R.O.C. Tel:886-2-2603-5321 Fax:886-2-2603-5325

1. Test Report Certification

Applicant: Advantech Co., Ltd.

EUT Description : Modular High-Resolution Das Card

Model Number : PCL-752
Serial Number : ProtoType
Power Supply : 230V/50Hz

MEASUREMENT PROCEDURE USED:

EN50081-2/1993 RULES AND EN55022/1994+A1/1995 RULES AND EN61000-3-2,-3

EN50082-2/1995 RULES AND EN61000-4 SERIES REGULATIONS

For EN50081-2/1993 and EN55022/1994+A1/1995:

The measurement shown in the attachment where made in accordance with the procedures indicated, and the maximum energy emitted by the equipment was found to be within the EN55022/1994+A1/1995 limits applicable.

For EN50082-2/1995 Rules and EN61000-4 Series Regulations:

The device described above was evaluated by Global EMC Standard Tech. Corp. to determine the severity levels of the device, and the severity levels of the device can endure and its performance criterion. The measurement results are contained in this test report and show that the EUT to be technically compliant with EN50082-2/1995/EN61000-4 Series regulations. Global EMC Standard Tech. Corp. recommends that the measurement results can pass performance criterion of above regulations.

GENERAL REMARK:

| The tests were performed | l according to the technical requirement of EUT. |
|--------------------------|--|
| ⊠ Electron-magnetic R | adiation Emission Interference (EN55022/55011) |

☑ Electron-magnetic Conduction Emission Interference (EN55022/55011)

☑ Disturbance Measurement (EN60555-2 & 3/ EN61000-3-2,-3)

☑ RF Field strength Susceptibility Measurement(EN 61000-4/ENV50140/ENV50204)

☑ Electrical Fast Transient/Burst Measurement (IEC1000-4-4/EN61000-4-4)

Surge Measurement (IEC1000-4-5/ EN61000-4-5)

☐ Low Frequency Signals Immunity (IEC1000-2-2)

☐ Magnetic Field Measurement (EN61000-4-8)

☑ Voltage Dips/Interruption Measurement (EN61000-4-11)

Sample Received Date : October. 27, 1998

Final Test Date : November. 05, 1998

Documented by : JOAN CHEIN

Test Engineer: Approve & Authorized Signer:

MILLER LEE TERRY CHING